

Search Notes

Application/Control No.

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Examiner

Thien F. Tran

Applicant(s)/Patent under
Reexamination

CHIOLA ET AL.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
.257	471-473 481-486	10/12/2005	TT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR